



Measurement of the systematic error for the IC electron analysis.

Calet TIM, 2020/02/03, Firenze

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Analysis parameters

- Flight data:

- L2, PASS 3.1, 201511 – 201807 (we are downloading the PASS4 now)

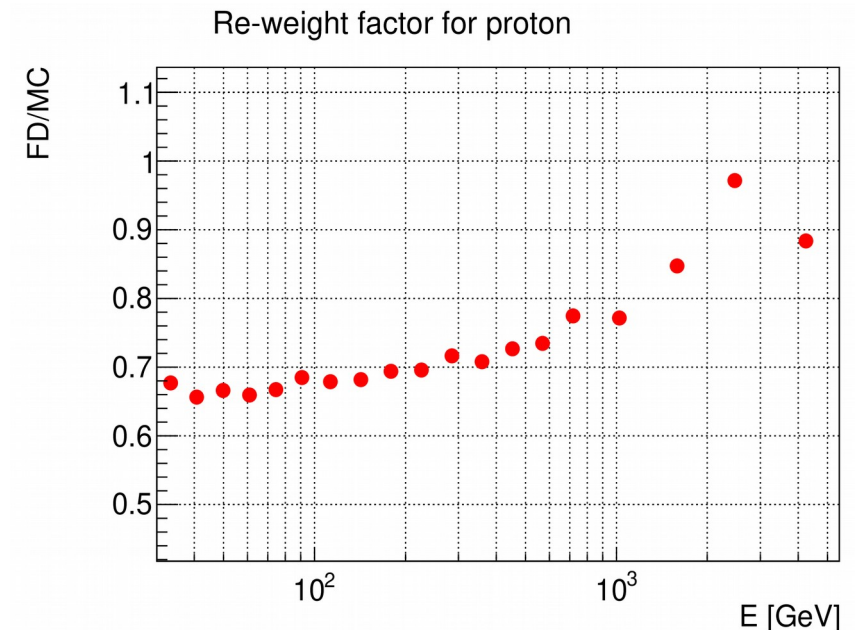
- MC Data:

- EPICS with X0 adjusted for the main analysis

- GEANT4 and EPICS with standard X0 are employed for the systematic errors.

- MC electron and proton spectra weighted according the AMS + CREAM fluxes.

- The number of protons is corrected according to the distribution in FD.



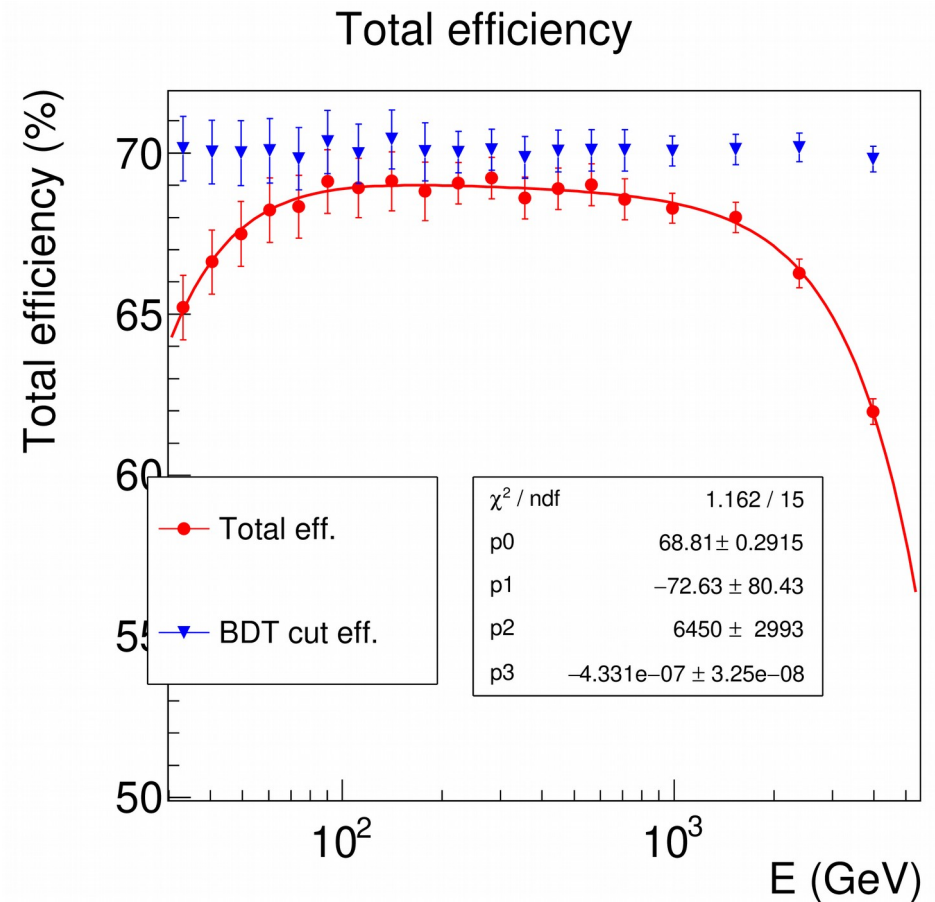
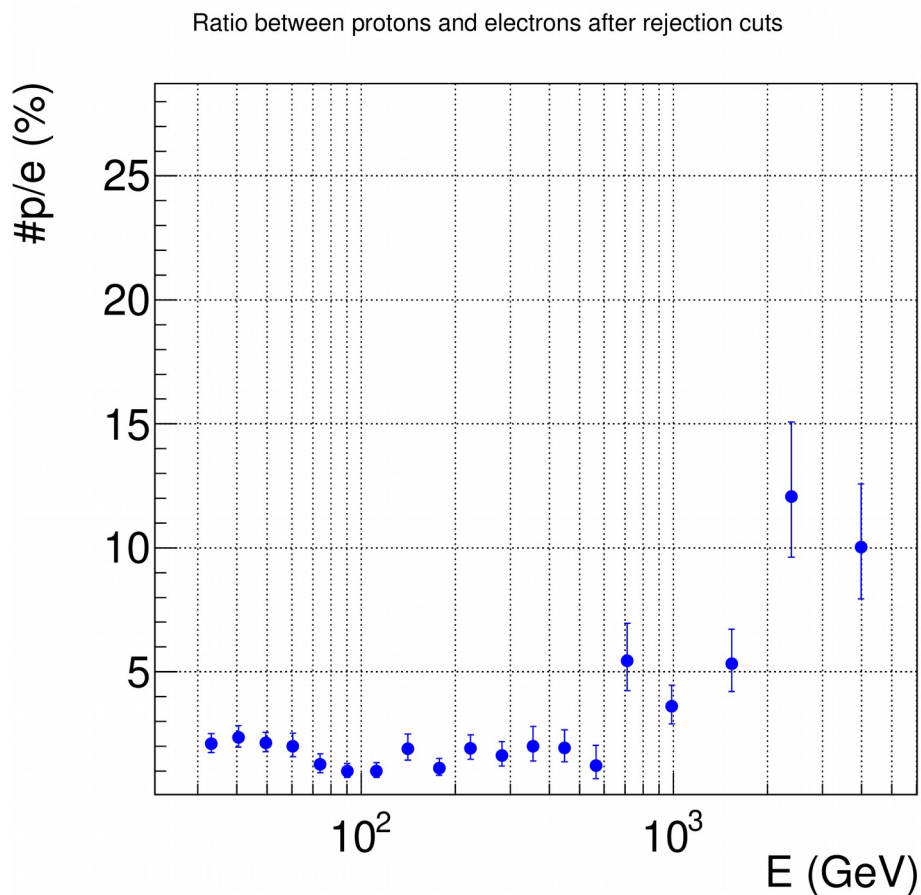
Base selections



- Software HET (more restrictive than hardware HET):
 - TASCX1 > 100 MIP, IMCX4,IMCY4 > 40 MIP.
- Good tracking with Kalman filter (IMCfitflag=3).
- **Track reconstructed within acc. E (Eugenio definition).**
- TASC layer concentration (see Pisa TIM)
- Consistency of the track in TASC (<2cm).
- Consistency between shower axis computed with the momentum method with the KF track (see KYOTO TIM for description).
- CHD cut, where the CHD peaks in proton MC are adjusted to match FD
- IMC shower concentration of last X and Y layer > 0.5.

Rejection cut

- Expected efficiency and contamination using MVA BDT with 70% efficiency.

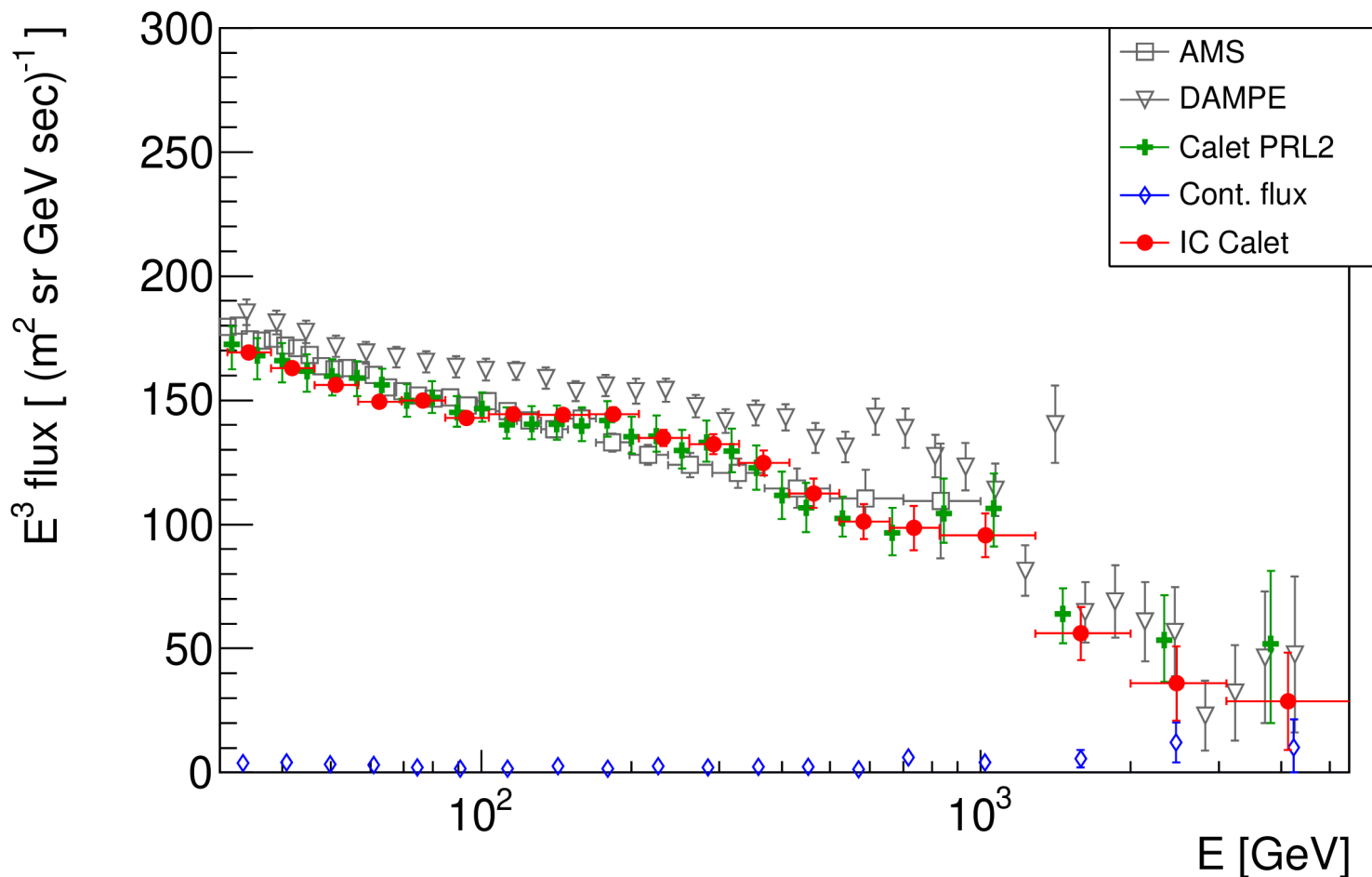


- Efficiency decreases due to the CHD and IMC show. conc. cuts.

Flux w/o systematic errors

● Good agreement with published result:

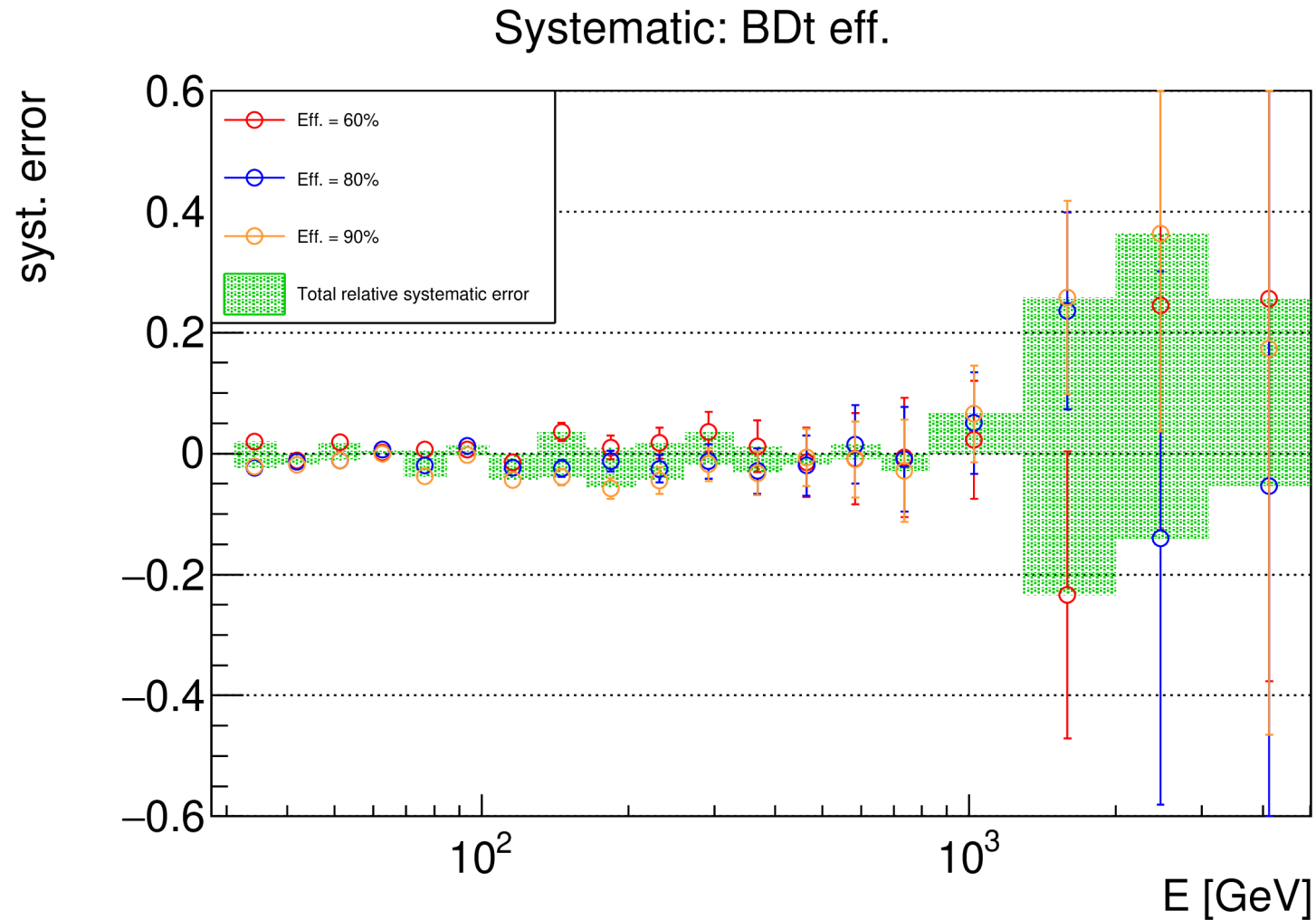
→ analysis diff.: all BDT, K cut is not used, RE shift is not applied so far.



- Systematic errors calculated as the ratio between different fluxes: for each analysis a new BDT training is performed, this is also a test of the BDT stability with respect to slightly different data samples.
- Systematic study so far (only energy dependent systematic are discussed here):
 - Selections: CHD, IMC shower concentration, SW trigger
 - Rejection cut efficiency: BDT, K cut used only below 1 TeV
 - MC model: EPICS w/o X0 adjusted, GEANT4
 - Different FD periods.

BDT efficiency

- BDT cut with 3 fixed efficiencies:

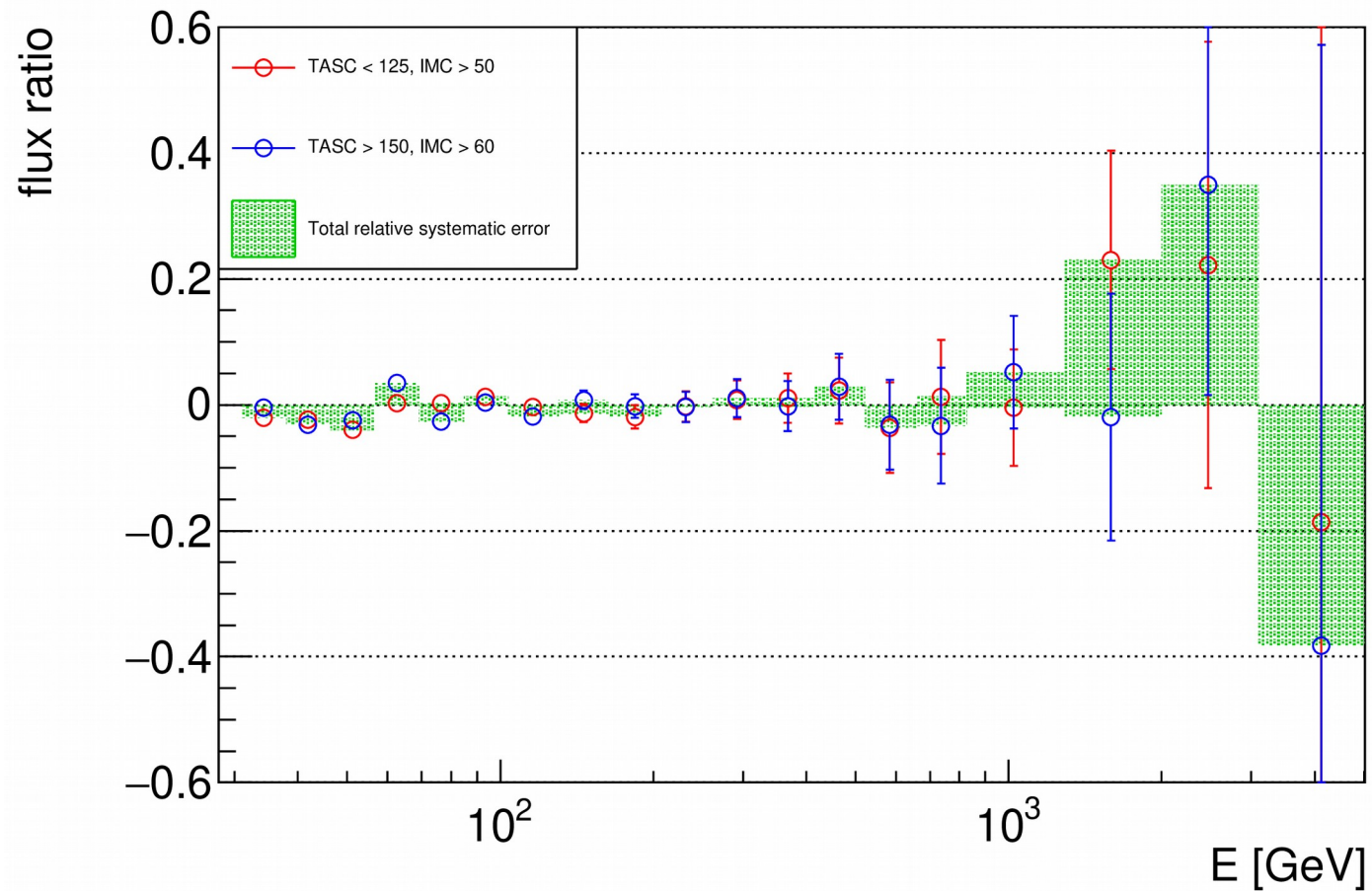


- Error bars are the stat. error of the flux

SW trigger

- Apply a SW trigger with higher thresholds

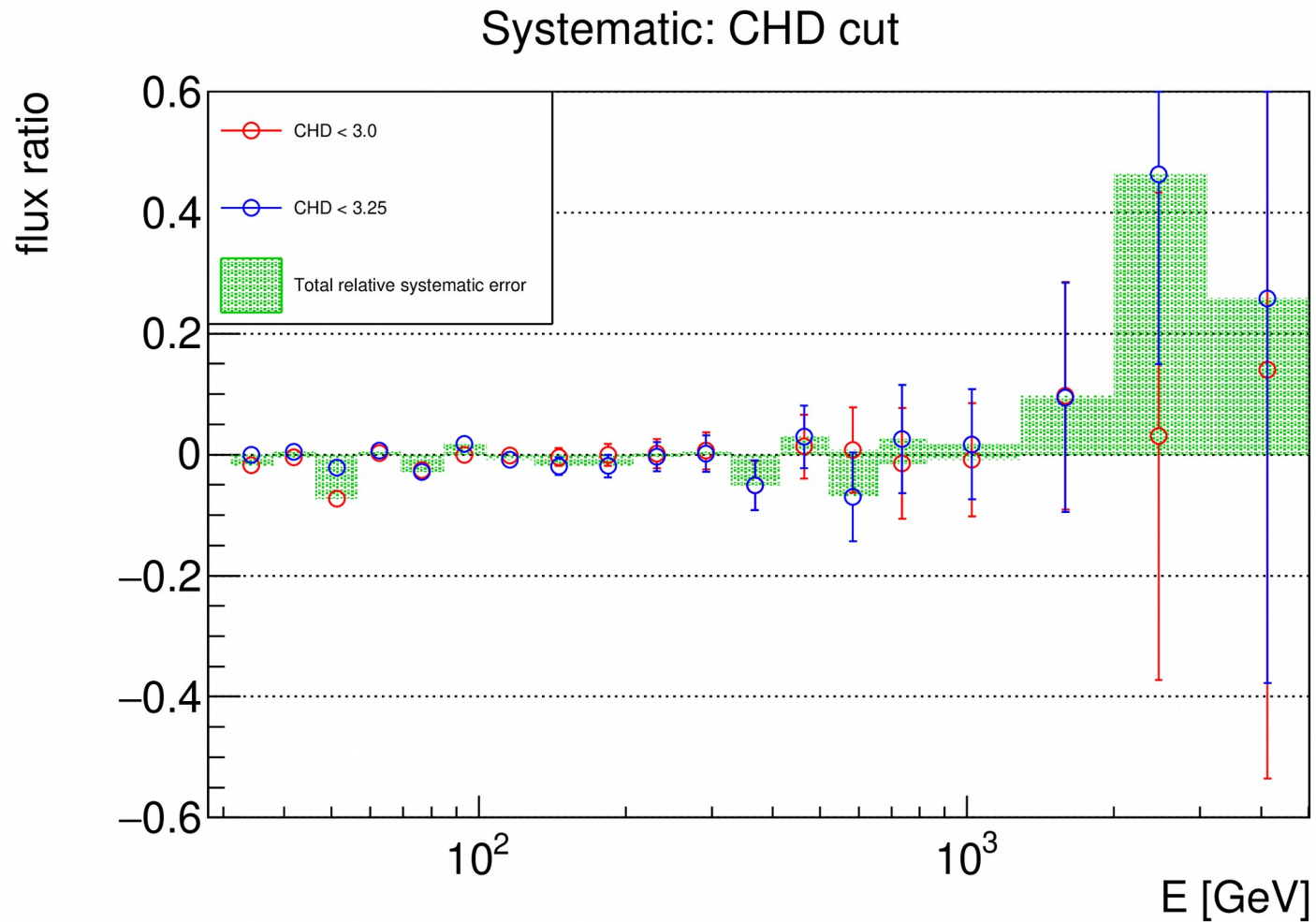
Systematic: trigger



- Error bars are the stat. error of the flux

CHD cut

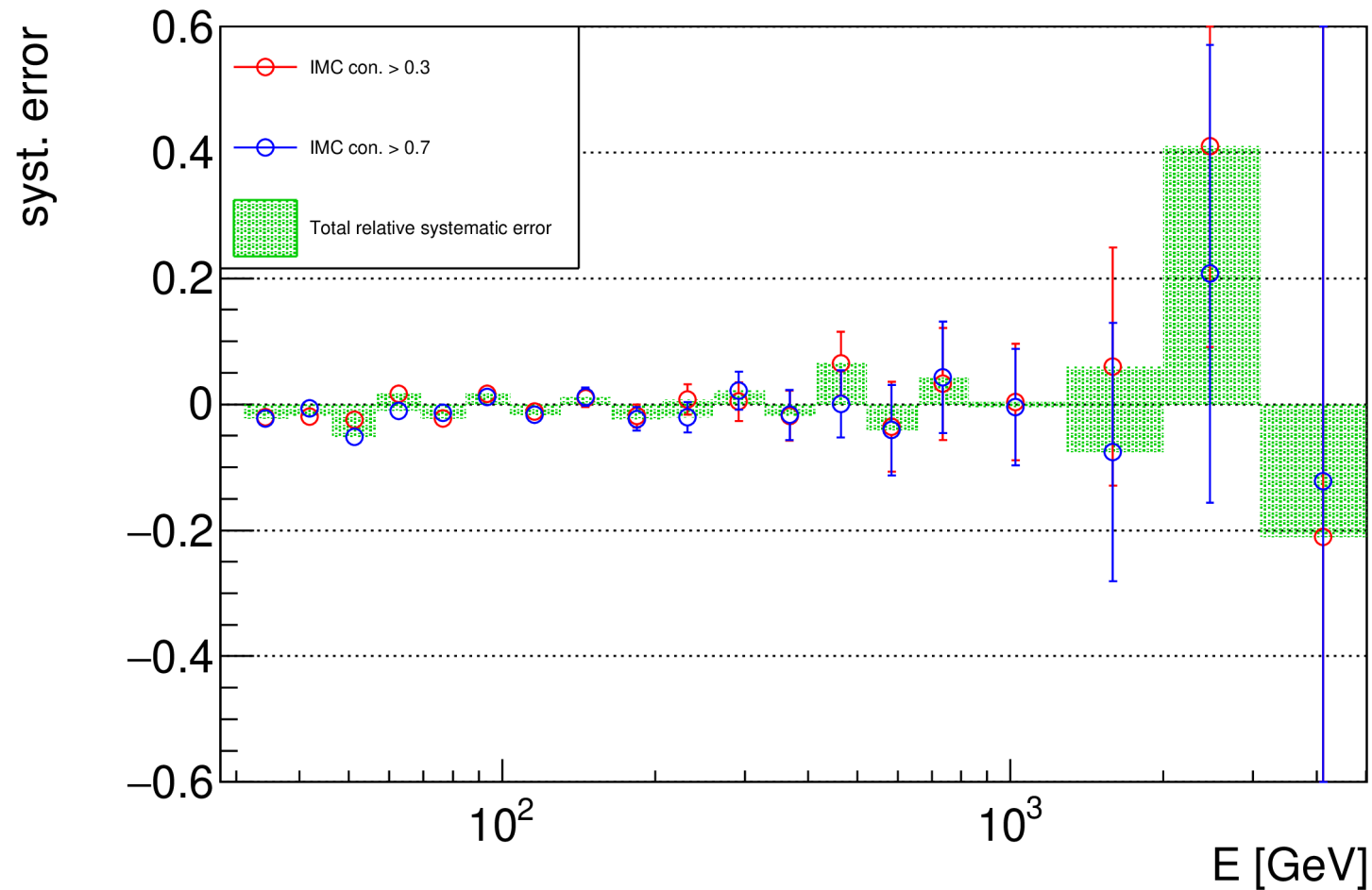
- Charge cut with smaller thresholds.



- Error bars are the stat. error of the flux

- IMC shower concentration with different thresholds

Systematic: IMC conc

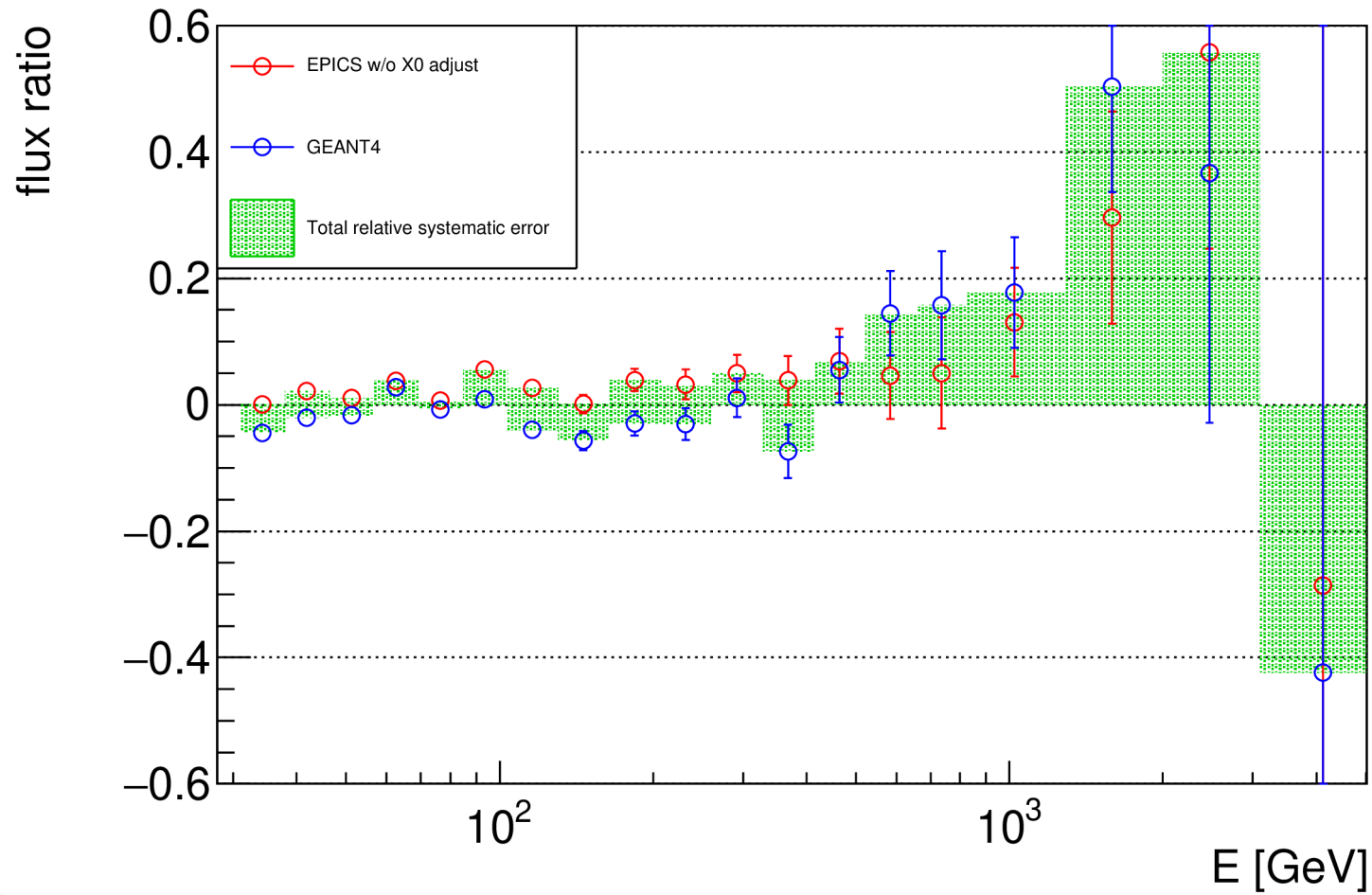


- Error bars are the stat. error of the flux

MC models

- GEANT4 and EPICS w/o X0 adjusted

Systematic: MC models

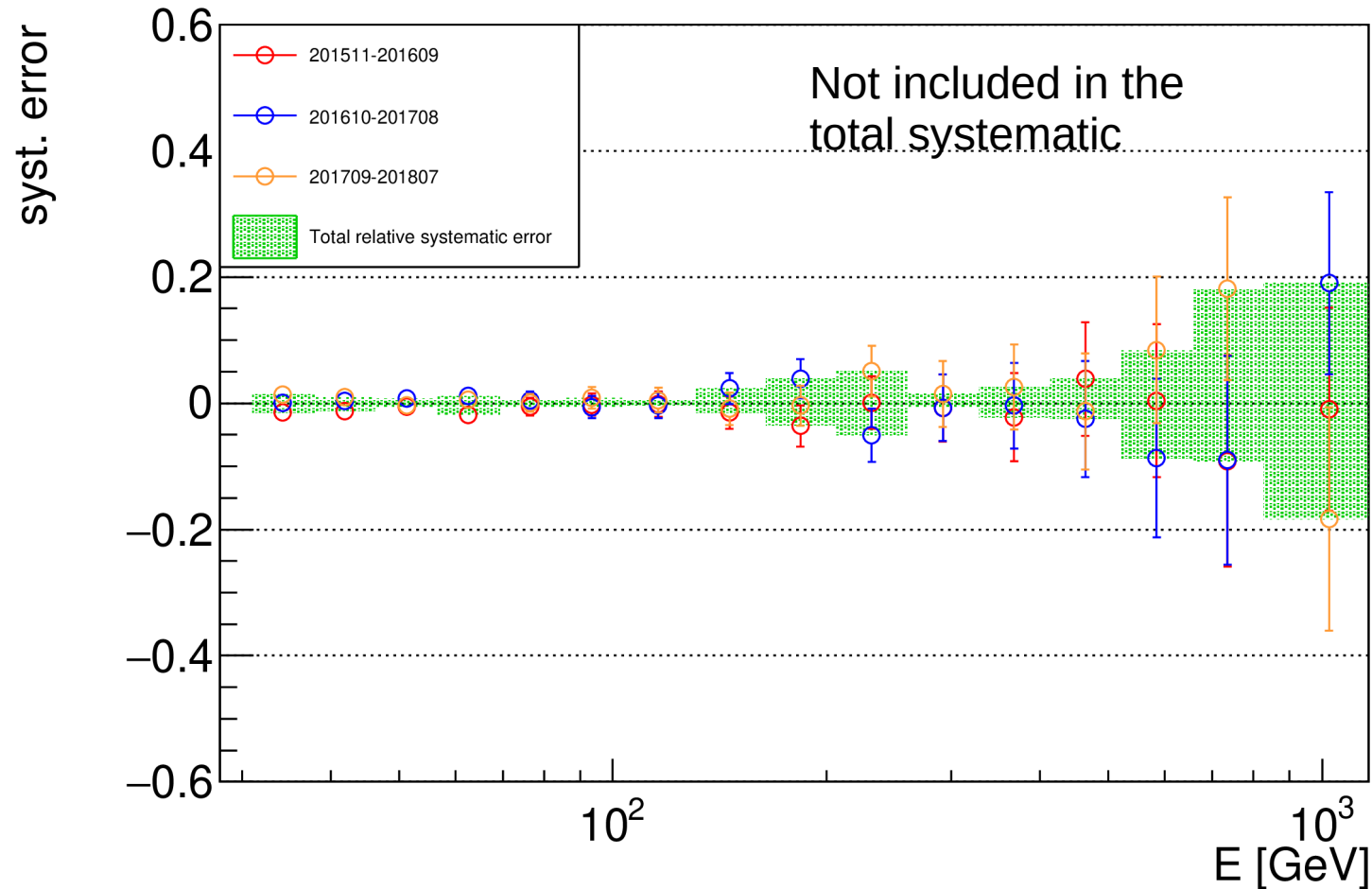


- Error bars are the stat. error of the flux

Stability

- Using different periods of FD

Systematic: stability

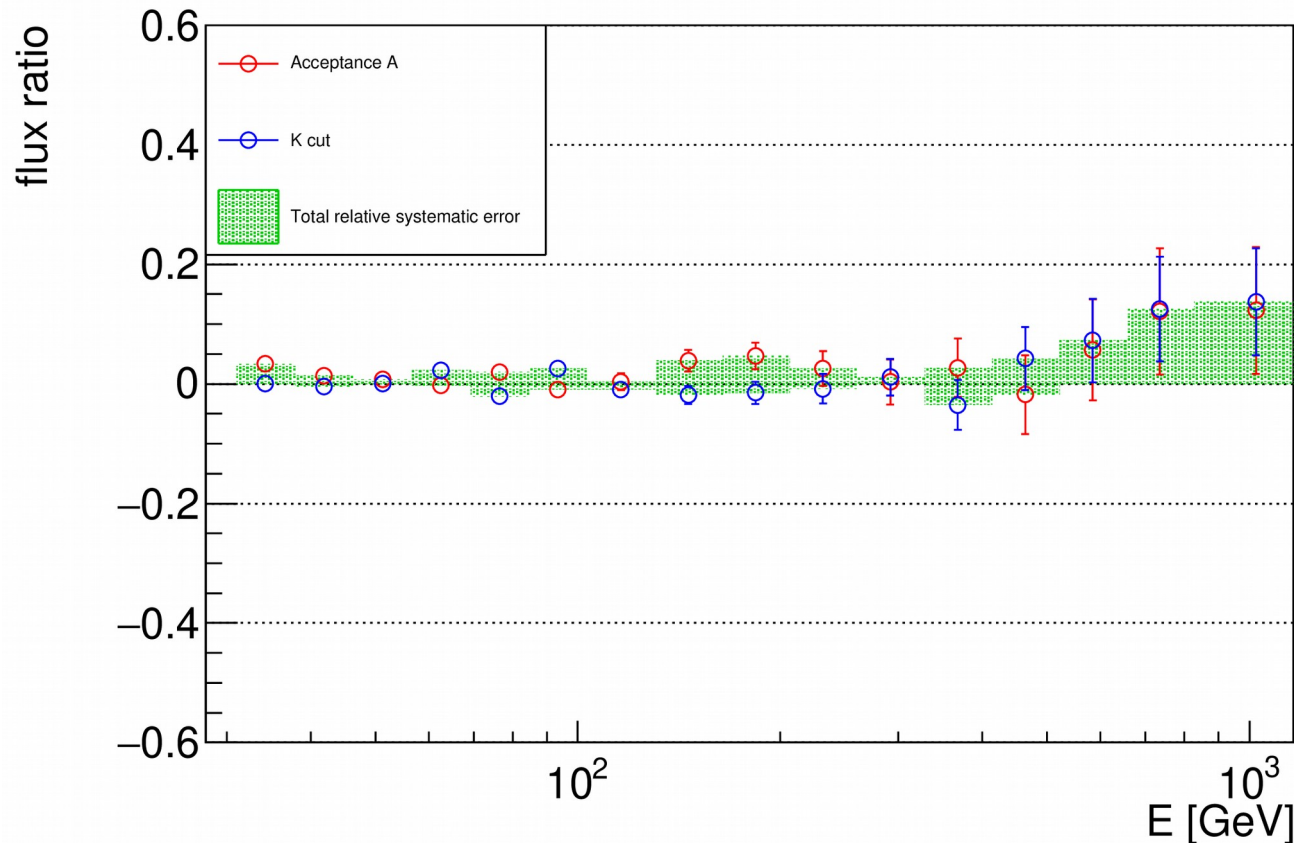


- Consistency check is possible below 1 TeV due to the limited statistic.

Acc A and K cut

- Using the acc A and the K cut

Systematic: acceptance and K cut

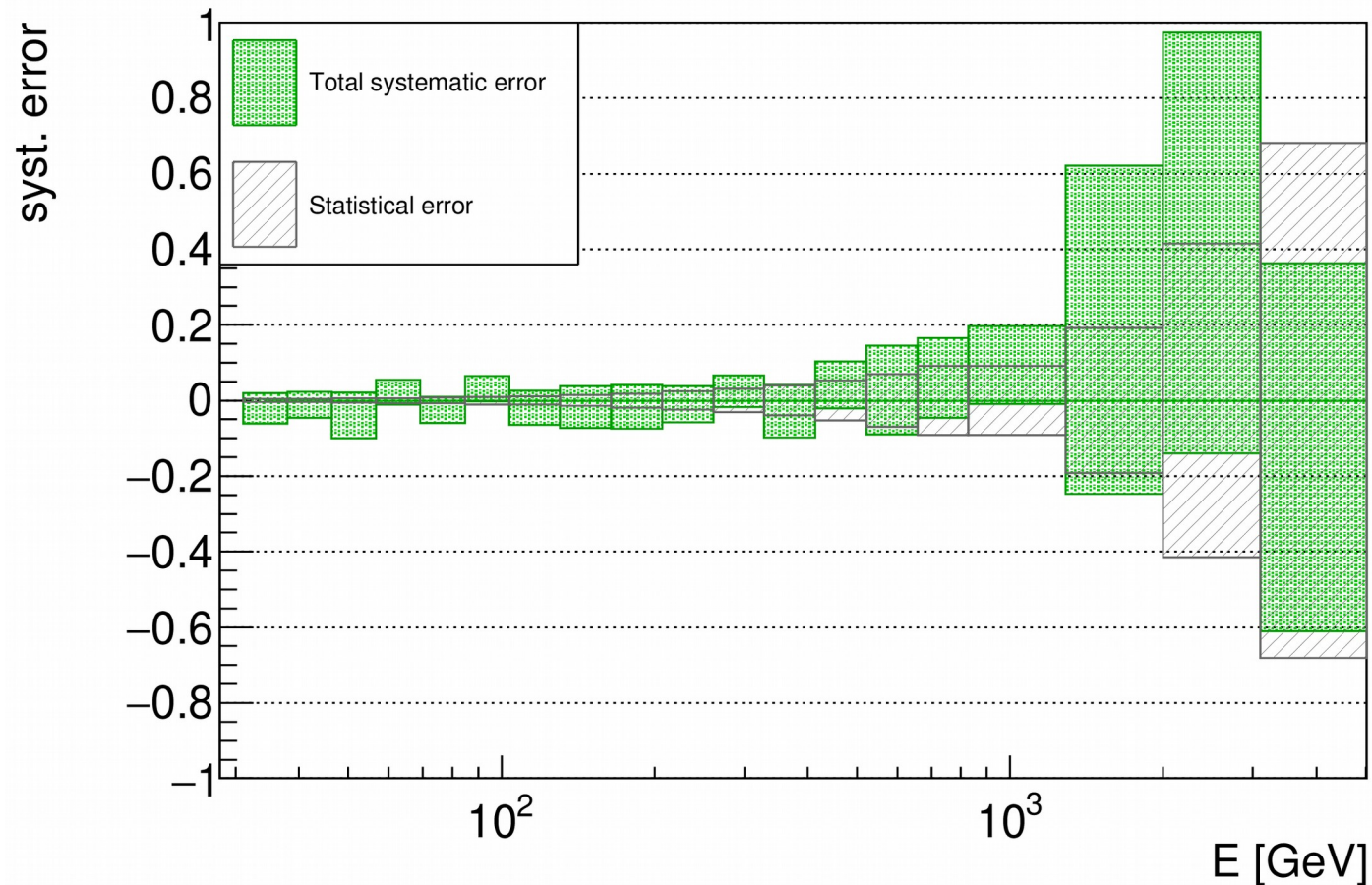


- Consistency check is possible below 1 TeV due to the limited statistic in acc A and a big proton contamination with K cut.

Total systematic error

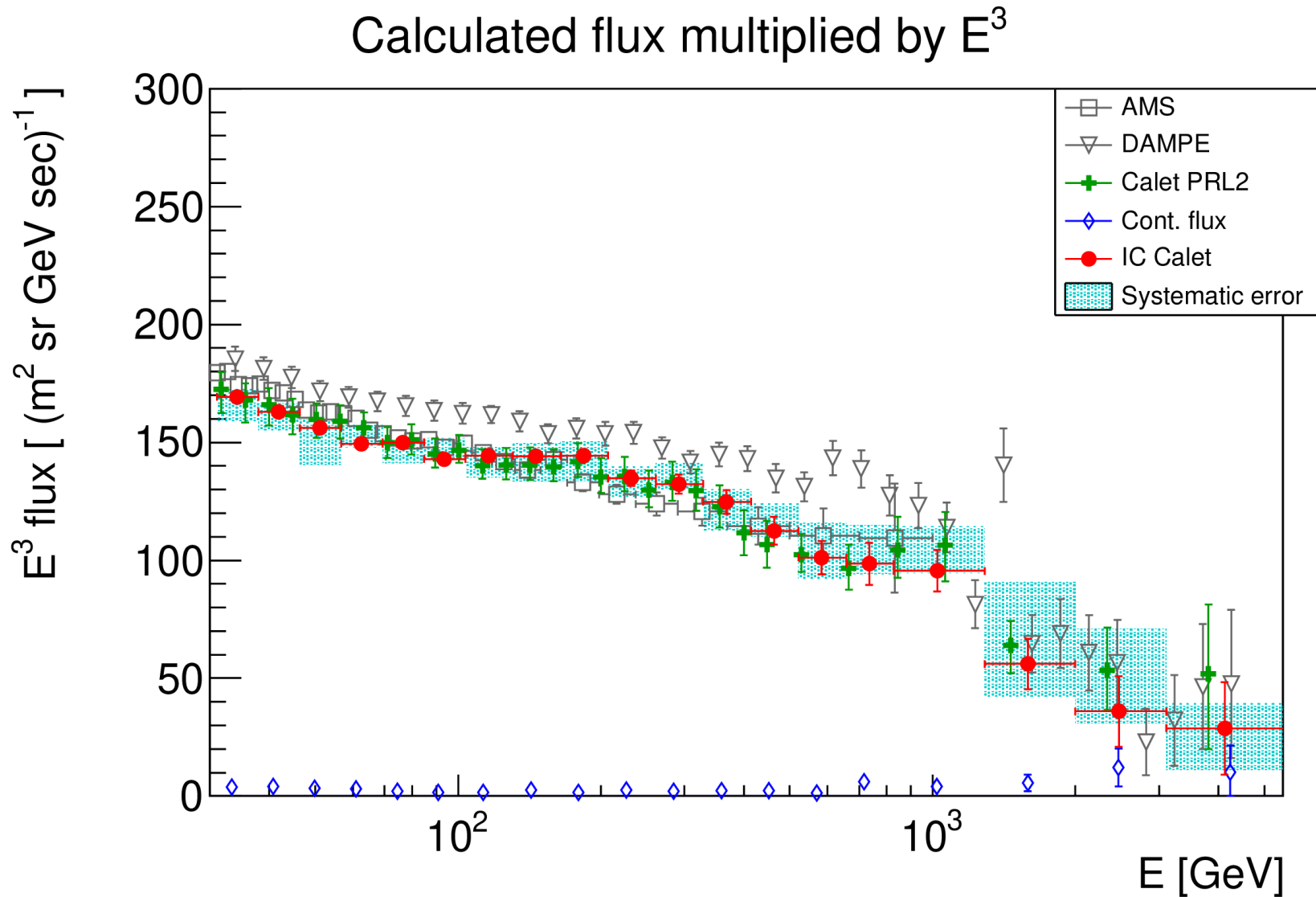
- Total systematic error excluding stability and Acc A and K cut above 1 TeV

Total relative systematic error



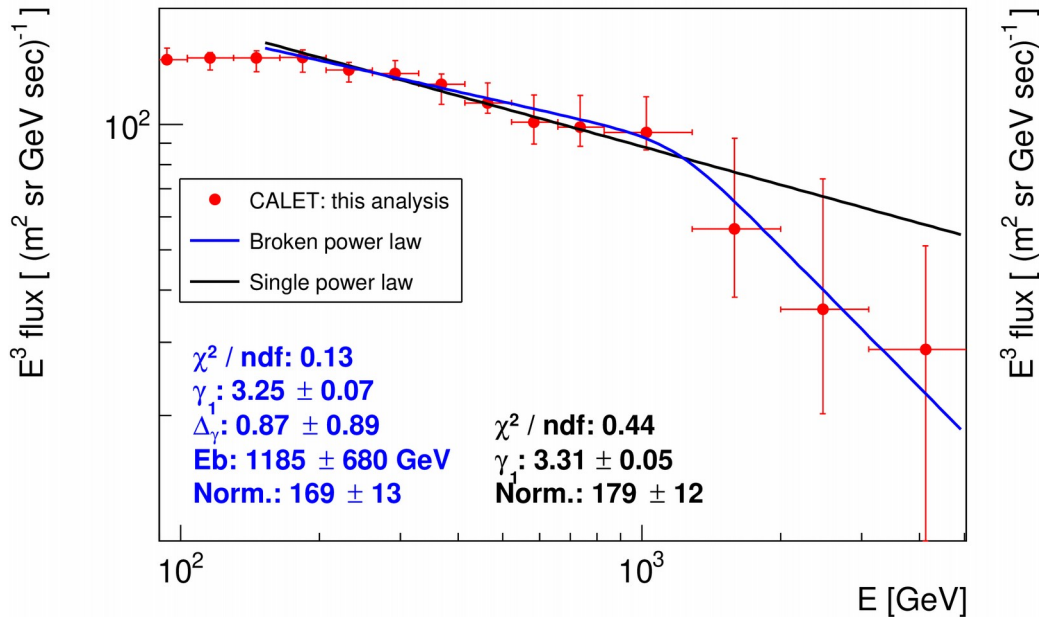
- $< \sim 10\%$ below 1 TeV, dominated by statistical error @ high energy

Flux with systematic error

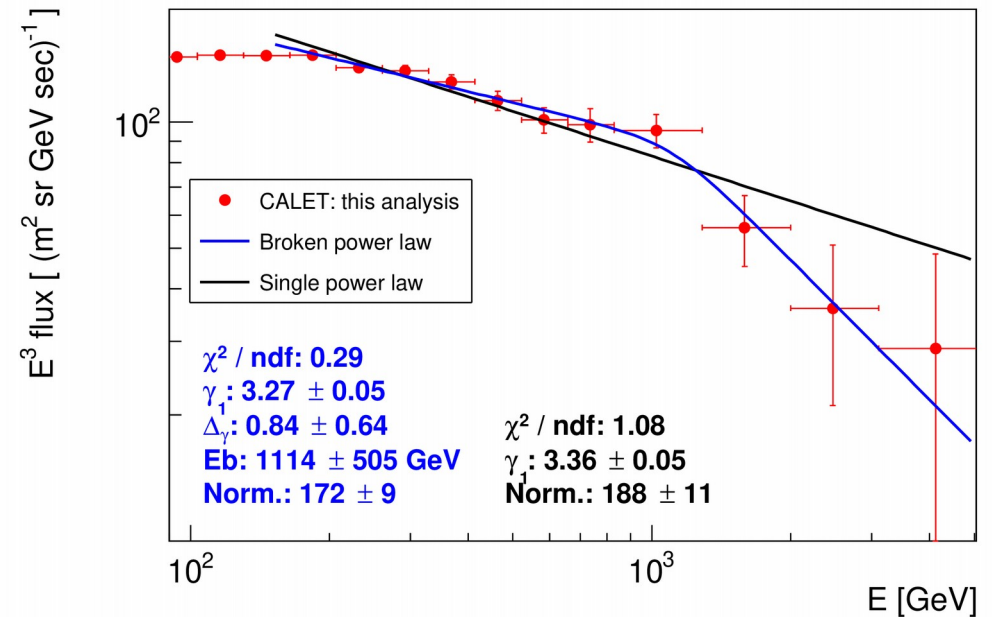


Tentative fit of the flux

Stat. + sys. errors



Stat. errors only



- Fit with a broken power law give the spectral brake @ $\sim 1 \text{ TeV}$ with big error
- Even the single power law well fit the data: this is mainly due to the limited statistic @ high energy.

Summary and prospective

- A consistent result with respect to the published one is obtained with IC independent analysis even if we use a different acceptance and BDT cut.
- A preliminary version of the systematic error was discussed:
 - Consistent with the published one below 1 TeV
 - Bigger @ high energy, but the systematic evaluation is mainly dominated by the limited statistic.
- Prospective:
 - PASS 4 and more statistic
 - Increase the MC FD agreement by adjusting some variables (RE, CHD ...)
 - Test new MVA algorithm with the flux. (BDT is not the best anymore)

- In our opinion there are two main efforts for the future electron analysis:
 - Reduce the error of the flux < 5 TeV to be able to distinguish between single power law and tentative spectral features @ 1 TeV.
 - We can start from the described analysis to decrease the systematic and statistical error.
 - Increases the energy range up to 10 TeV:
 - We think that the standard analysis is not enough thus we should employ different procedures (ev. by ev., ...)